

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Application No.: 09/833,084 Confirmation No.: 8866
First Named Inventor: Ibrahim Abdulhalim et al. Filing Date: April 10, 2001
Group Art Unit: 1775 Examiner: Unknown
Atty. Docket No.: TNCR.196US0
Title: PERIODIC PATTERNS AND TECHNIQUE TO CONTROL MISALIGNMENT
Assignee: KLA-TENCOR CORPORATION

San Francisco, California
March 27, 2003

COMMISSIONER FOR PATENTS
Washington, D. C. 20231

**SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97, and 1.98, Applicants call the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

☒ Copies of the documents listed on the accompanying Form PTO-1449 are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

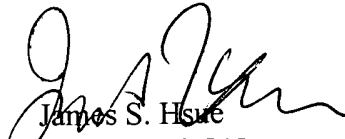


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This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required.

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Respectfully submitted,


James S. Hsue
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U.S. Department of Commerce, Patent and Trademark Office	Atty Docket No.	Application No.
	TNCR.196US0	09/833,084
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Applicant(s)	Confirmation No.
	Ibrahim Abdulhalim, et al.	8866
	Filing Date	Group
	April 10, 2001	1775

U.S. Patent Documents

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	4,200,395	04/29/80	Smith et al.	356	356	
AB	4,332,473	01/05/82	Ono	356	356	
AD	4,757,207	07/12/88	Chappelow et al.	250	491.1	
AE						
AF						
AG						
AI						
AJ						
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AK						
AD						
AE						
AG						
AH						
AI						

Foreign Patent Documents

							Translation	
	Document	Date	Country	Class	Subclass	Yes	No	
AL	WO 01/73824 A1	10/04/01	PCT					
AM								

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AQ	R. Pforr, et al., "In-Process Image Detecting Technique For Determination Of Overlay, And Image Quality For ASM-L Wafer Stepper", <i>SPIE Vol. 1674 Optical/Laser Microlithography V</i> (1992) pp. 594-608
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Examiner

Date Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.